

# MOS FIELD EFFECT TRANSISTOR 2SJ603

# SWITCHING P-CHANNEL POWER MOS FET

#### **DESCRIPTION**

The 2SJ603 is P-channel MOS Field Effect Transistor designed for solenoid, motor and lamp driver.

#### **FEATURES**

• Super low on-state resistance:

 $R_{DS(on)1} = 48 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -10 \text{ V, ID} = -13 \text{ A)}$ 

 $R_{DS(on)2} = 75~m\Omega$  MAX. (Vgs = -4.0~V,~Id = -13~A)

· Low input capacitance:

 $C_{iss} = 1900 \text{ pF TYP.} (V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V})$ 

Built-in gate protection diode

#### **ORDERING INFORMATION**

PART NUMBER	PACKAGE
2SJ603	TO-220AB
2SJ603-S	TO-262
2SJ603-ZJ	TO-263
2SJ603-Z	TO-220SMD Note

**Note** TO-220SMD package is produced only in Japan.

#### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	-60	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓20	V
Drain Current (DC) (Tc = 25°C)	I <sub>D(DC)</sub>	∓25	Α
Drain Current (pulse) Note1	ID(pulse)	<b>∓70</b>	Α
Total Power Dissipation (Tc = 25°C)	PT	50	W
Total Power Dissipation (T <sub>A</sub> = 25°C)	PT	1.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C
Single Avalanche Current Note2	las	-25	Α
Single Avalanche Energy Note2	Eas	62.5	mJ

**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty cycle  $\leq$  1%

**2.** Starting T<sub>ch</sub> = 25°C, V<sub>DD</sub> = -30 V, R<sub>G</sub> = 25  $\Omega$ , V<sub>GS</sub> = -20  $\rightarrow$  0 V

(TO-220AB)



(TO-262)



(TO-263, TO-220SMD)



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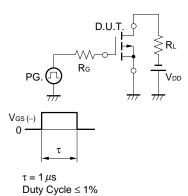
#### **ELECTRICAL CHARACTERISTICS (TA = 25°C)**

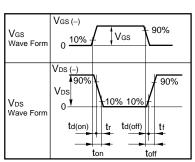
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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	Vps = -60 V, Vgs = 0 V			-10	μΑ
Gate Leakage Current	lgss	$V_{GS} = \mp 20 \text{ V}, V_{DS} = 0 \text{ V}$			∓10	μΑ
Gate Cut-off Voltage	V <sub>GS(off)</sub>	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$	-1.5	-2.0	-2.5	٧
Forward Transfer Admittance	yfs	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -13 A	10	21		S
Drain to Source On-state Resistance	RDS(on)1	V <sub>G</sub> S = -10 V, I <sub>D</sub> = -13 A		38	48	mΩ
	RDS(on)2	Vgs = -4.0 V, ID = -13 A		53	75	mΩ
Input Capacitance	Ciss	Vps = -10 V		1900		pF
Output Capacitance	Coss	V <sub>G</sub> s = 0 V		350		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		140		pF
Turn-on Delay Time	td(on)	V <sub>DD</sub> = -30 V, I <sub>D</sub> = -13 A		10		ns
Rise Time	tr	V <sub>G</sub> S = −10 V		11		ns
Turn-off Delay Time	td(off)	$R_G = 0 \Omega$		66		ns
Fall Time	tr			20		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = -48 V		38		nC
Gate to Source Charge	Qgs	V <sub>GS</sub> = -10 V		7		nC
Gate to Drain Charge	Q <sub>GD</sub>	I <sub>D</sub> = -25 A		10		nC
Body Diode Forward Voltage	V <sub>F</sub> (S-D)	IF = 25 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 25 A, VGS = 0 V		49		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ μs		100		nC

#### **TEST CIRCUIT 1 AVALANCHE CAPABILITY**

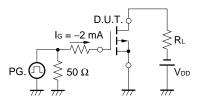
# $V_{GS} = -20 \rightarrow 0 \text{ V}$ $V_{DD}$ $V_{DD}$

#### **TEST CIRCUIT 2 SWITCHING TIME**

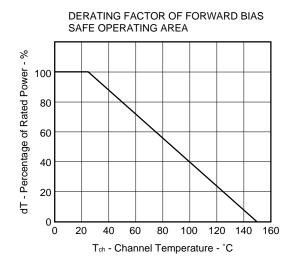


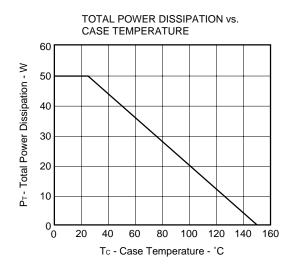


#### **TEST CIRCUIT 3 GATE CHARGE**

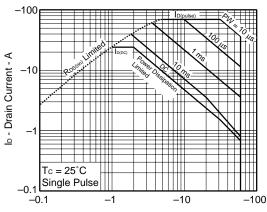


#### TYPICAL CHARACTERISTICS (TA = 25°C)



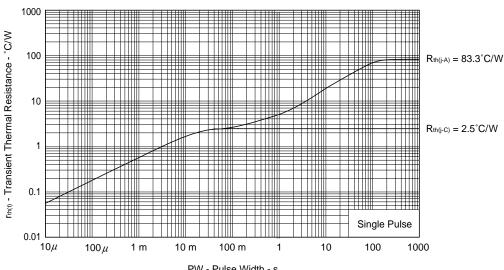


#### FORWARD BIAS SAFE OPERATING AREA



V<sub>DS</sub> - Drain to Source Voltage - V

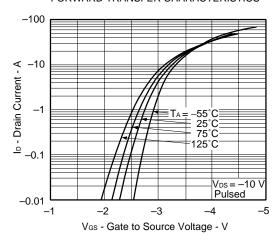
#### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



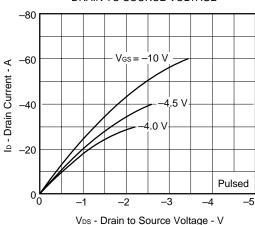
PW - Pulse Width - s

Data Sheet D14648EJ3V0DS

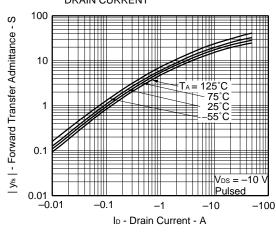
#### FORWARD TRANSFER CHARACTERISTICS



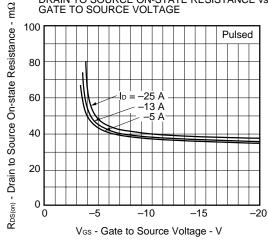
#### DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



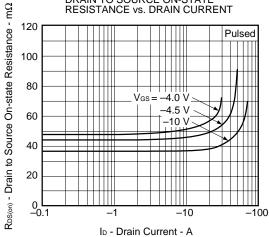
## FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



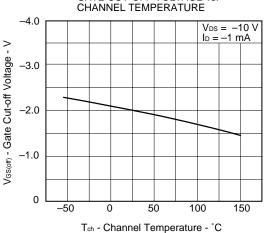
## DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

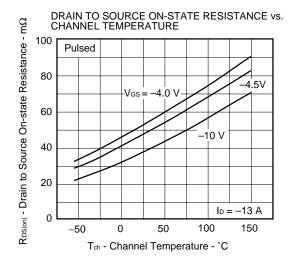


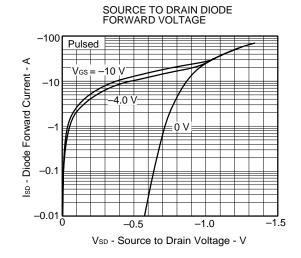
# DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

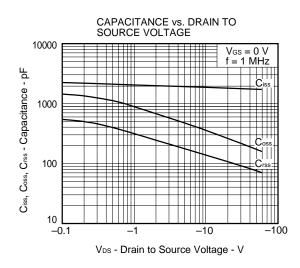


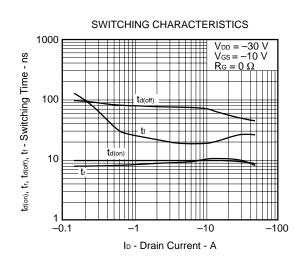
#### GATE CUT-OFF VOLTAGE vs.

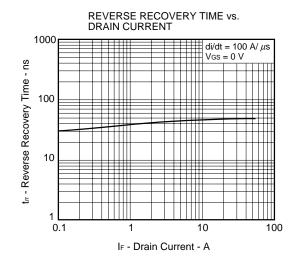


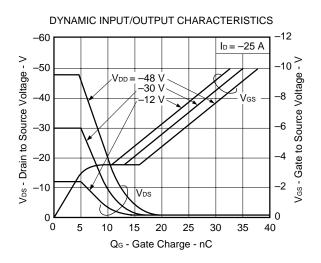


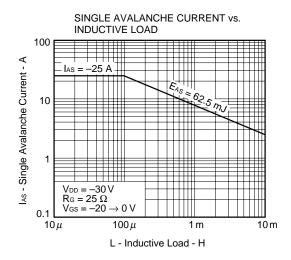


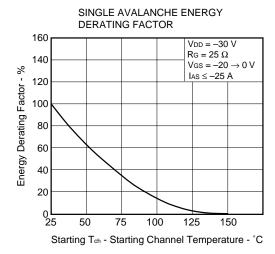








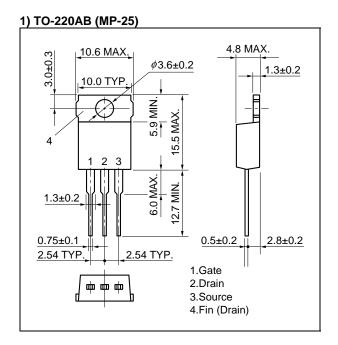


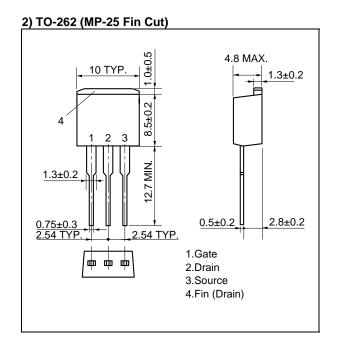


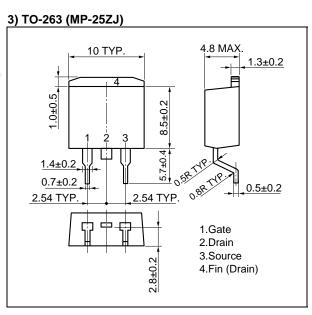
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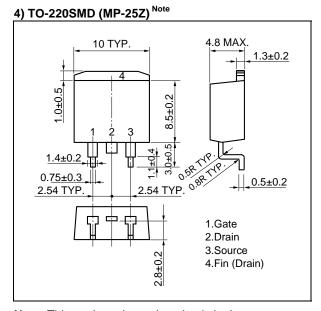


#### **★ PACKAGE DRAWINGS (Unit: mm)**



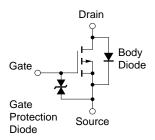






Note This package is produced only in Japan.

#### **EQUIVALENT CIRCUIT**



**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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